 arcn Notes	٠.

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/531,245	SENKEVICH ET AL.	
Examiner	Art Unit	
SEVED MASOUD	1722	

MALEKZADEH

SEARCHED				
Class	Subclass	Date	Examiner	
117	84	2/1/2007	SMM	
117	88	2/1/2007	SMM	
117	89	2/1/2007	SMM	
117	99	2/1/2007	SMM	
117	102	2/2/2007	SMM	
117	104	2/2/2007	SMM	
117	105	2/2/2007	SMM	
			·	
			,	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		,	
	<u> </u>	-	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Use Palm Intranet to search inventor's name	2/1/2007	SMM
Use text search through East to find prior art. Examiner used key words such as "Atomic Layer Deposition"	2/1/2007	SMM